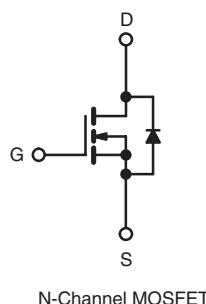
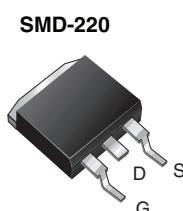


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	100	
$R_{DS(on)}$ (Ω)	$V_{GS} = 5.0$ V	0.16
Q_g (Max.) (nC)	28	
Q_{gs} (nC)	3.8	
Q_{gd} (nC)	14	
Configuration	Single	



FEATURES

- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic Level Gate Drive
- $R_{DS(on)}$ Specified at $V_{GS} = 4$ V and 5 V
- 175 °C Operating Temperature
- Lead (Pb)-free Available


RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SMD-220 is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on resistance in any existing surface mount package. The SMD-220 is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

ORDERING INFORMATION

Package	SMD-220	SMD-220
Lead (Pb)-free	IRL530SPbF SiHL530S-E3	IRL530STRRPbFa SiHL530STR-E3a
SnPb	IRL530S SiHL530S	- -

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	100	
Gate-Source Voltage	V_{GS}	± 10	V
Continuous Drain Current	I_D	15	A
		11	
Pulsed Drain Current ^a	I_{DM}	60	
Linear Derating Factor		0.59	W/°C
		0.025	
Single Pulse Avalanche Energy ^b	E_{AS}	290	mJ
Repetitive Avalanche Current ^a	I_{AR}	15	A
Repetitive Avalanche Energy ^a	E_{AR}	8.8	mJ
Maximum Power Dissipation	P_D	88	W
		3.7	
Peak Diode Recovery dV/dt ^c	dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 175	
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 25$ V, starting $T_J = 25$ °C, $L = 1.9$ mH, $R_G = 25 \Omega$, $I_{AS} = 15$ A (see fig. 12).

c. $I_{SD} \leq 15$ A, $dI/dt \leq 140$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.

d. 1.6 mm from case.

e. When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W
Maximum Junction-to Ambient (PCB mount) ^a	R _{thJA}	-	40	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.7	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		100	-	-	V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, I _D = 1 mA		-	0.14	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		1.0	-	2.0	V	
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 10 V		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V		-	-	25	μA	
		V _{DS} = 80 V, V _{GS} = 0 V, T _J = 150 °C		-	-	250		
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 5.0 V	I _D = 9.0 A ^b	-	-	0.16	Ω	
		V _{GS} = 4.0 V	I _D = 7.5 A ^b	-	-	0.22		
Forward Transconductance	g _f	V _{DS} = 50 V, I _D = 9.0 A ^b		6.4	-	-	S	
Dynamic								
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	930	-	pF	
Output Capacitance	C _{oss}			-	250	-		
Reverse Transfer Capacitance	C _{rss}			-	57	-		
Total Gate Charge	Q _g	V _{GS} = 5.0 V	I _D = 15 A, V _{DS} = 80 V, see fig. 6 and 13 ^b	-	-	28	nC	
Gate-Source Charge	Q _{gs}			-	-	3.8		
Gate-Drain Charge	Q _{gd}			-	-	14		
Turn-On Delay Time	t _{d(on)}			-	4.7	-		
Rise Time	t _r	V _{DD} = 50 V, I _D = 15 A, R _G = 12 Ω, R _D = 32 Ω, see fig. 10 ^b		-	100	-	ns	
Turn-Off Delay Time	t _{d(off)}			-	22	-		
Fall Time	t _f			-	48	-		
Internal Drain Inductance	L _D			-	4.5	-	nH	
Internal Source Inductance	L _S	Between lead, 6 mm (0.25") from package and center of die contact		-	7.5	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	60		
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 15 A, V _{GS} = 0 V ^b		-	-	2.5	V	
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 15 A, dI/dt = 100 A/μs ^b		-	150	200	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.93	1.4	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.

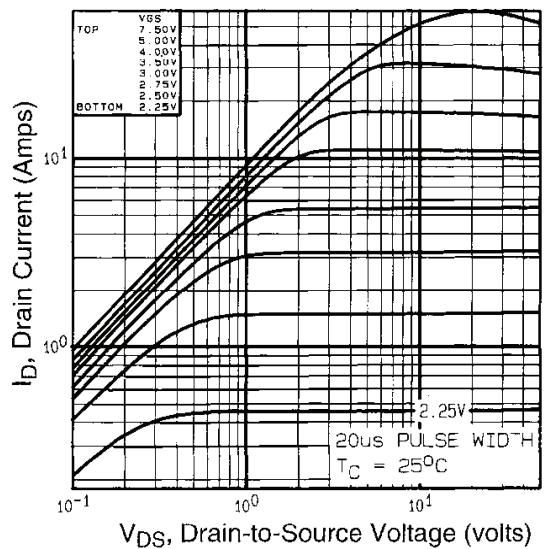
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


Fig. 1 - Typical Output Characteristics, $T_C = 25^\circ\text{C}$

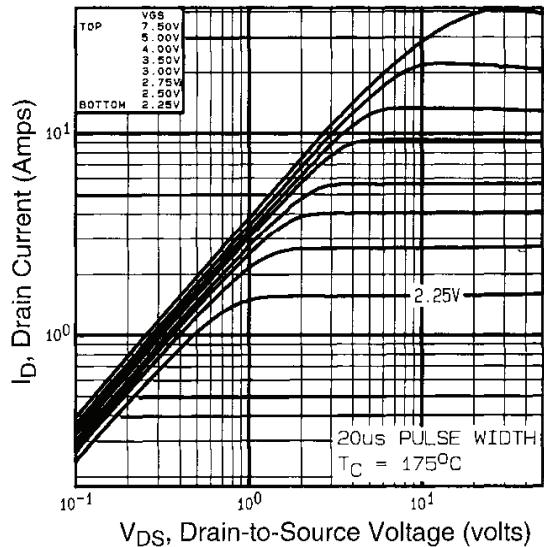
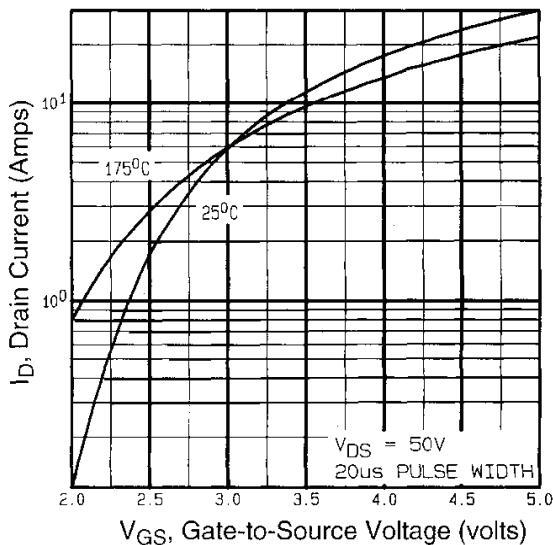
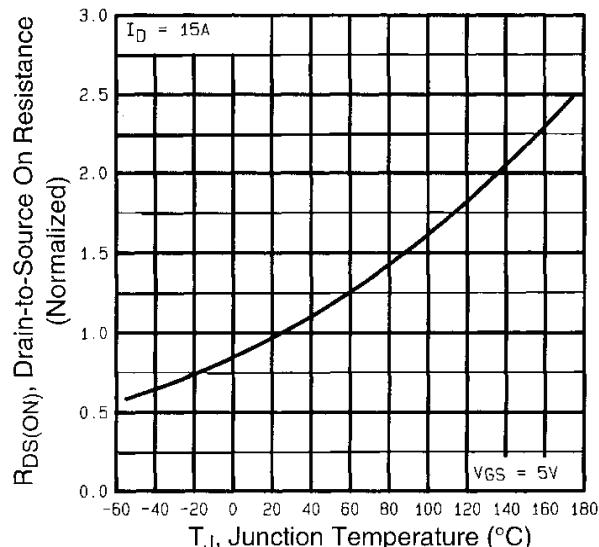


Fig. 2 - Typical Output Characteristics, $T_C = 175^\circ\text{C}$



IRL530S, SiHL530S



Vishay Siliconix

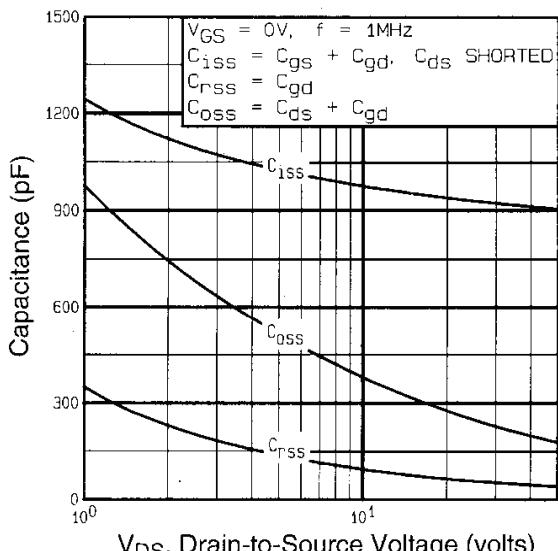


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

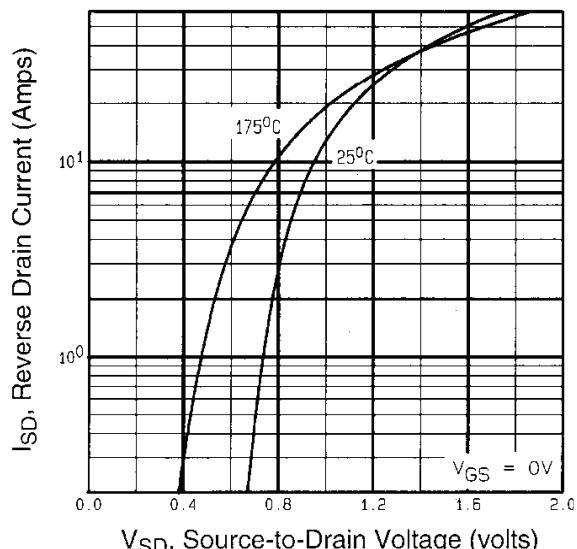


Fig. 7 - Typical Source-Drain Diode Forward Voltage

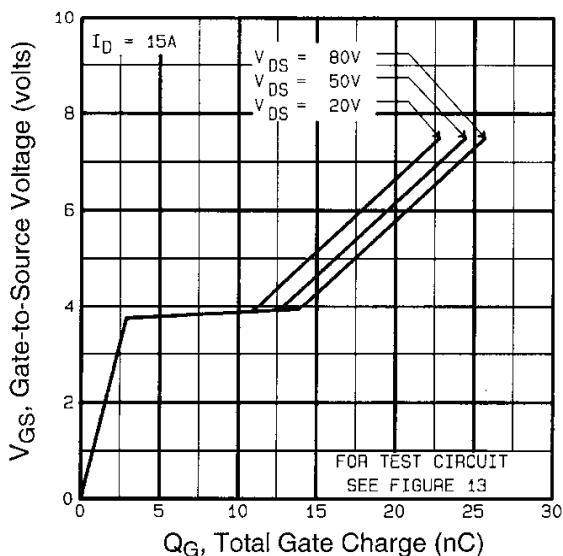


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

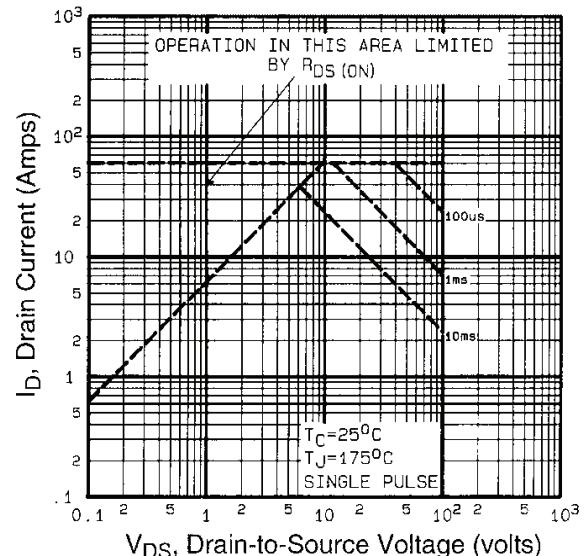


Fig. 8 - Maximum Safe Operating Area

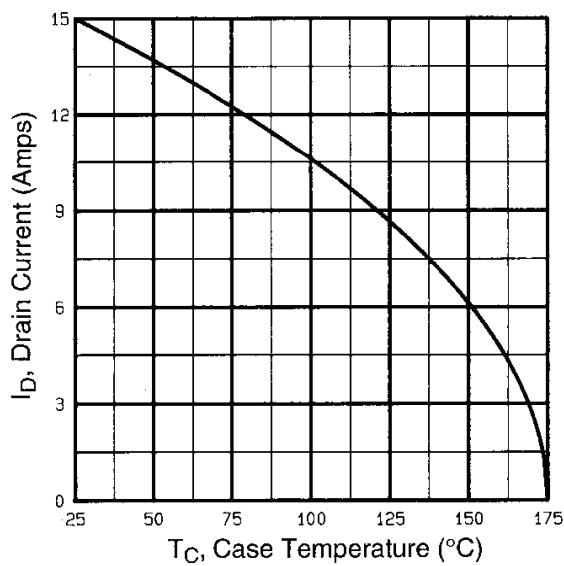


Fig. 9 - Maximum Drain Current vs. Case Temperature

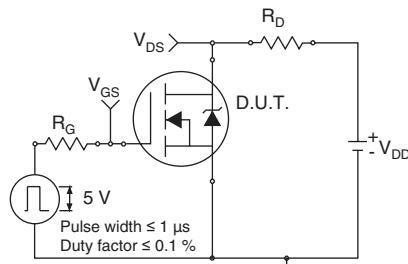


Fig. 10a - Switching Time Test Circuit

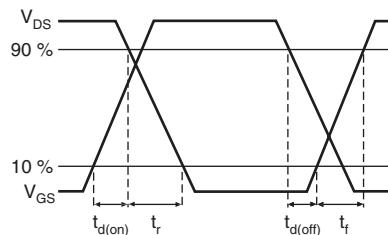


Fig. 10b - Switching Time Waveforms

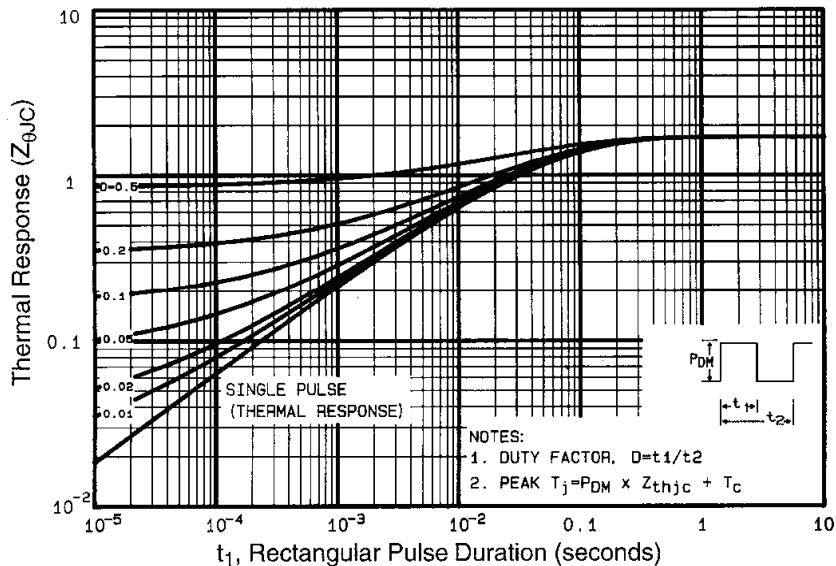


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

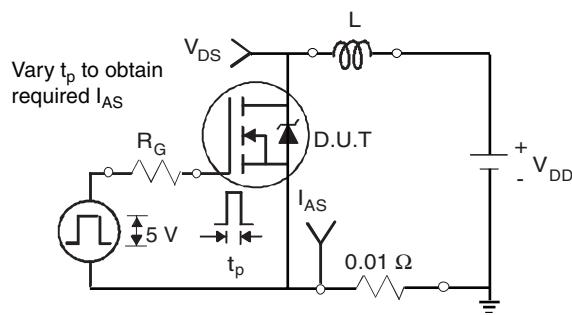


Fig. 12a - Unclamped Inductive Test Circuit

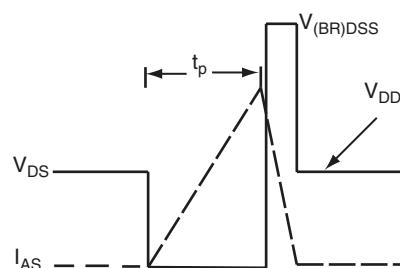


Fig. 12b - Unclamped Inductive Waveforms

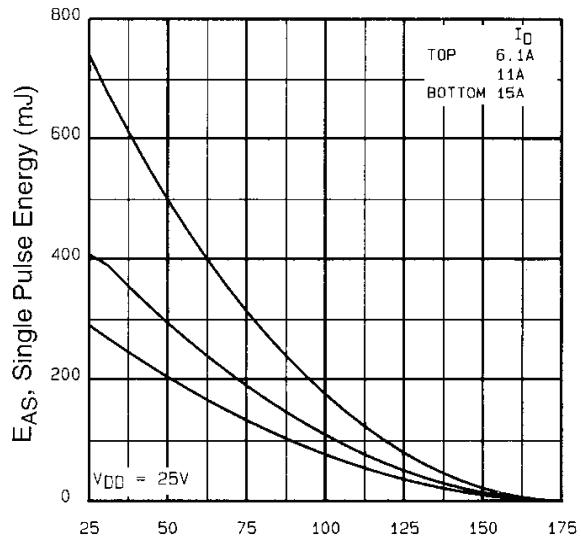


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

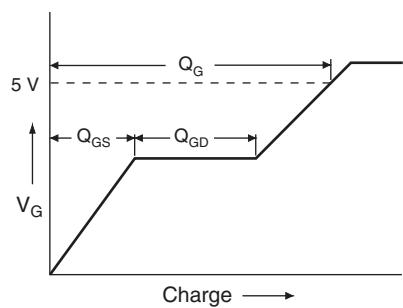


Fig. 13a - Basic Gate Charge Waveform

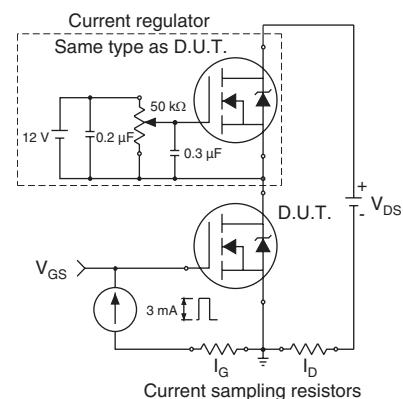
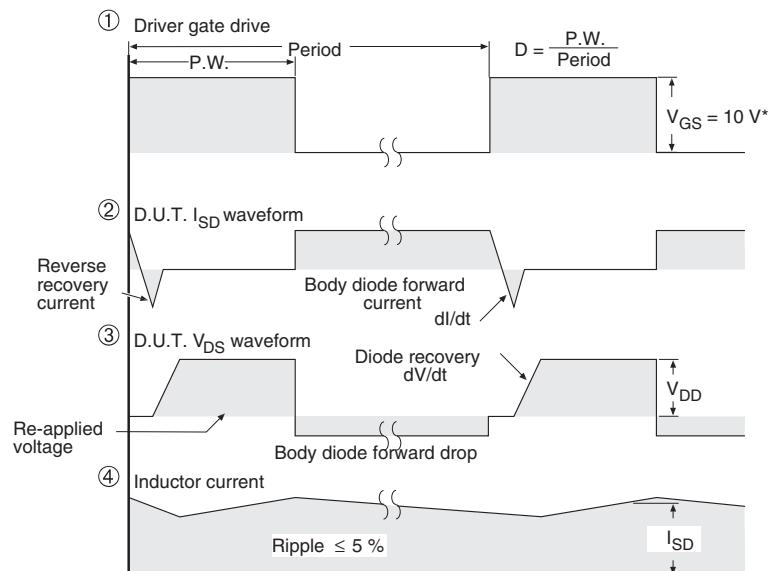
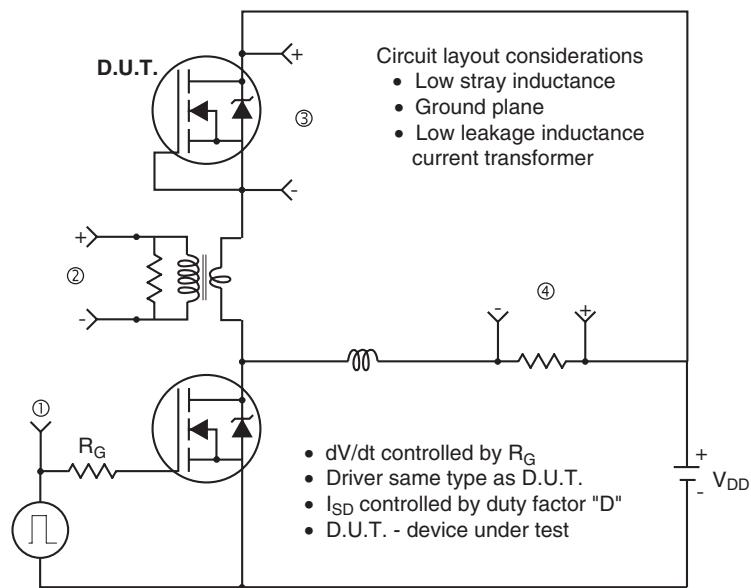


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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